

PARTIAL GOOD INTEGRATED CIRCUIT AND METHOD OF TESTING SAME

ABSTRACT

An integrated circuit, including: a multiplicity of macro-circuits, each macro-
5 circuit having the same function; a fuse bank containing a multiplicity of fuses, the state
of the fuses storing test data indicating at least which macro-circuits failed a test; and
means for preventing utilization of failing macro-circuits during operation of the
integrated circuit and a method generating a partial good integrated circuit, the method
including: providing an integrated circuit have a multiplicity of macro-circuits arranged in
10 one or more groups, each macro-circuit having the same function and a fuse bank
containing fuses; testing each macro-circuit prior to a fuse programming operation;
programming the fuses in the fuse bank in order to store data indicating at least which
macro-circuits failed the testing step; and preventing utilization of each failing macro-
circuit during operation of the integrated based on the data stored in the fuse bank.